

Notice of References Cited	Application/Control No. 10/634,168		Applicant(s)/Patent Under Reexamination CHUNG ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,667,220	12-2003	Jeon et al.	438/400
*	B	US-5,188,987	02-1993	Ogino, Masanobu	438/675
*	C	US-4,313,809	02-1982	Benyon et al.	204/192.25
*	D	US-5,880,013	03-1999	Yang et al.	438/514
*	E	US-4,912,065	03-1990	Mizuno et al.	438/301
*	F	US-6,716,727	04-2004	Walther, Steven R.	438/514
*	G	US-5,429,989	07-1995	Fiordalice et al.	438/648
*	H	US-5,753,555	05-1998	Hada, Hiromitsu	438/300
*	I	US-6,093,625	07-2000	Wagner et al.	438/514
*	J	US-6,849,555	02-2005	Lee et al.	438/715
*	K	US-6,797,559	09-2004	Lee et al.	438/239
*	L	US-6,767,834	07-2004	Chung et al.	438/709
*	M	US-6,858,529	02-2005	Chung et al.	438/629

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 1-202817	08-1989	JP	ENOMOTO, YOSHINARI	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	KR 2004057600 A, Koo, JC, 2 July 2004
*	V	Van Zant, Peter, Microchip Fabrication, 4th ed. McGraw-Hill, pp. 333, 340-1.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,509,263	01-2003	Park et al.	438/672
*	B	US-6,844,259	01-2005	Cheong, Woo-Seock	438/657
*	C	US-6,030,894	02-2000	Hada et al.	438/675
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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